

High-radiance LDP source for mask-inspection application

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USHIO INC. / *Fraunhofer ILT

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Lighting—Edge Technologies

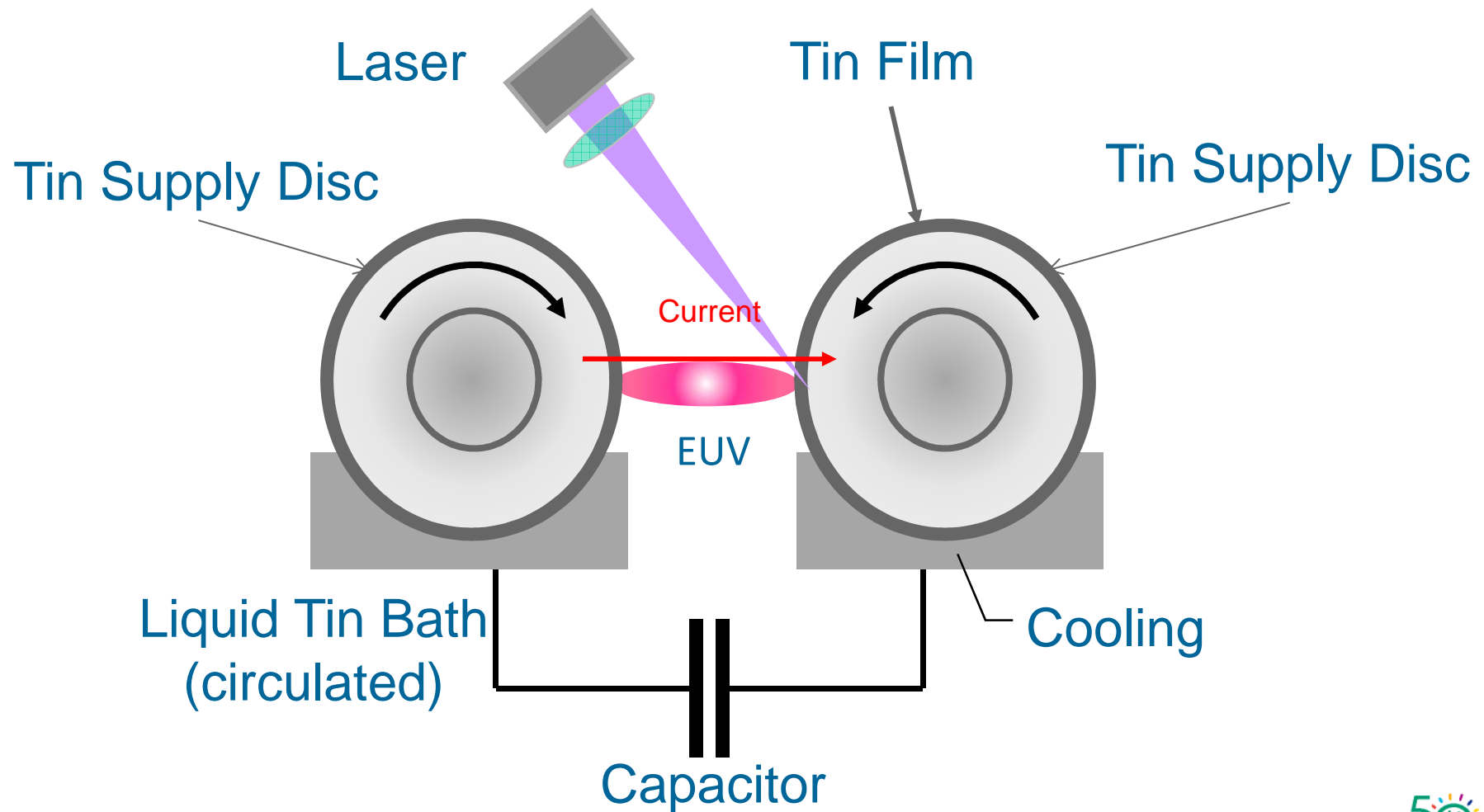


Thank you
50th Anniversary

I N D E X

- **Basic Principle of LDP source**
- **Source brightness of LDP source**
- **Source cleanliness**
- **Summary**

Sn + Laser + Discharge: Key for high radiance



LDP: High-radiance, clean, stable EUV photon to the tool

Neutral debris

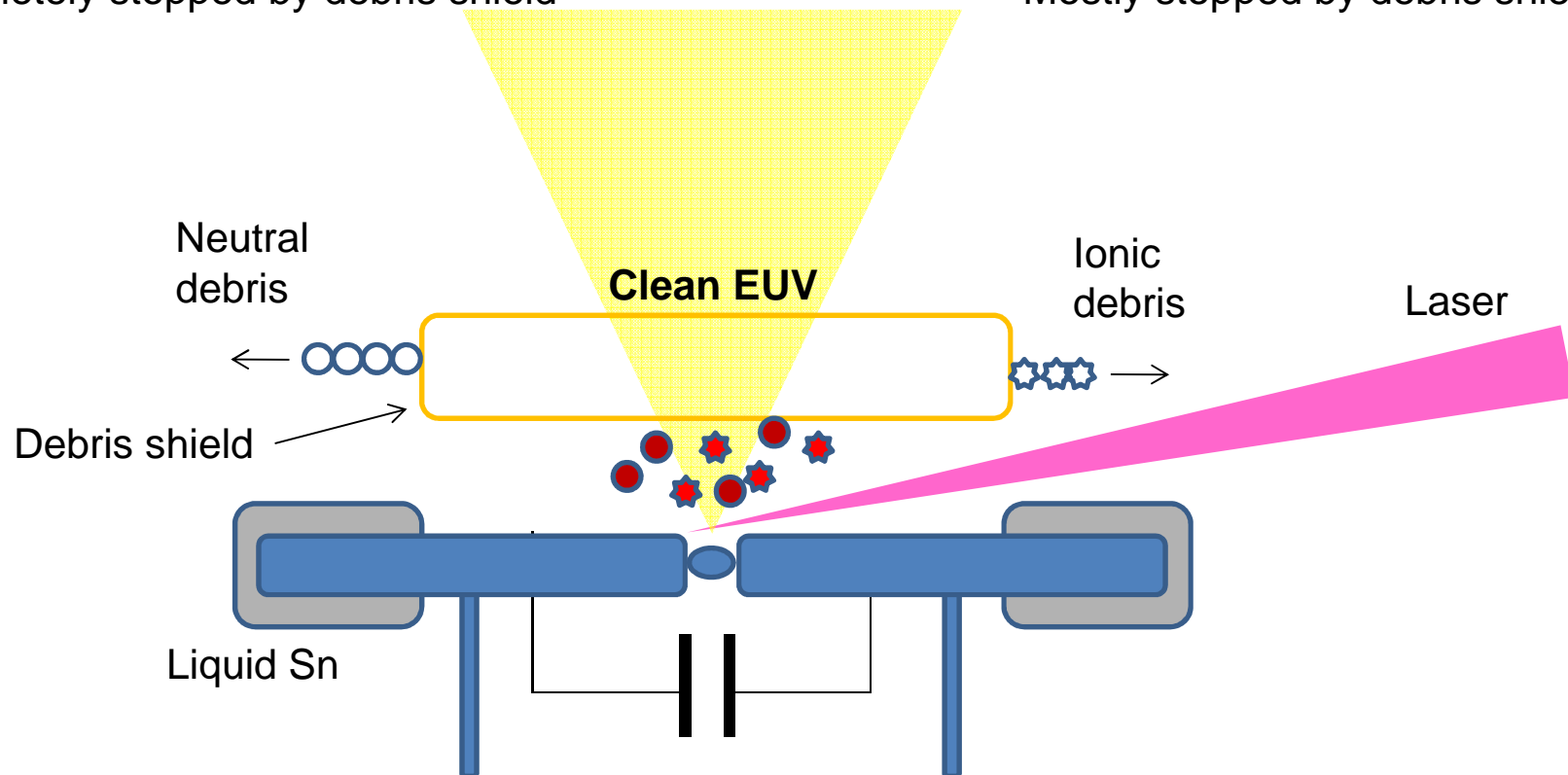
(Macro/microscopic particles, gaseous debris)

- Completely stopped by debris shield

Ionic debris

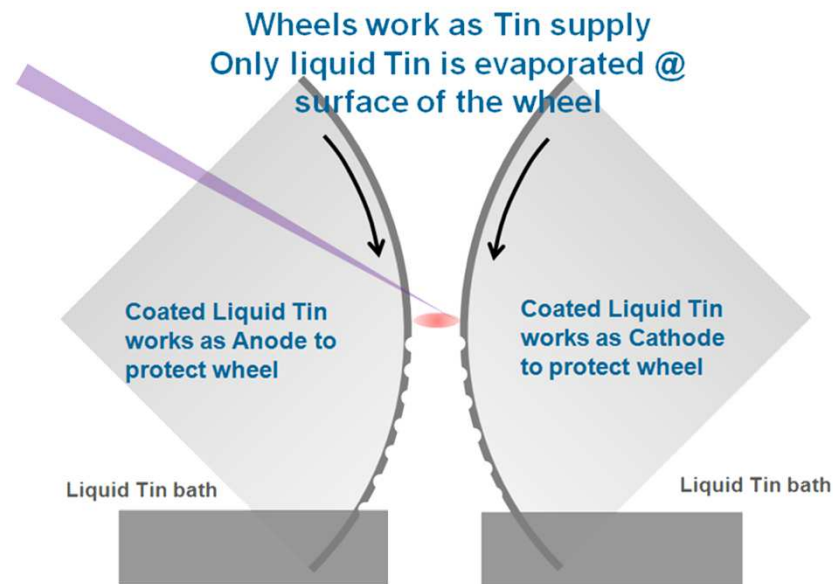
(Charged particles)

- Mostly stopped by debris shield

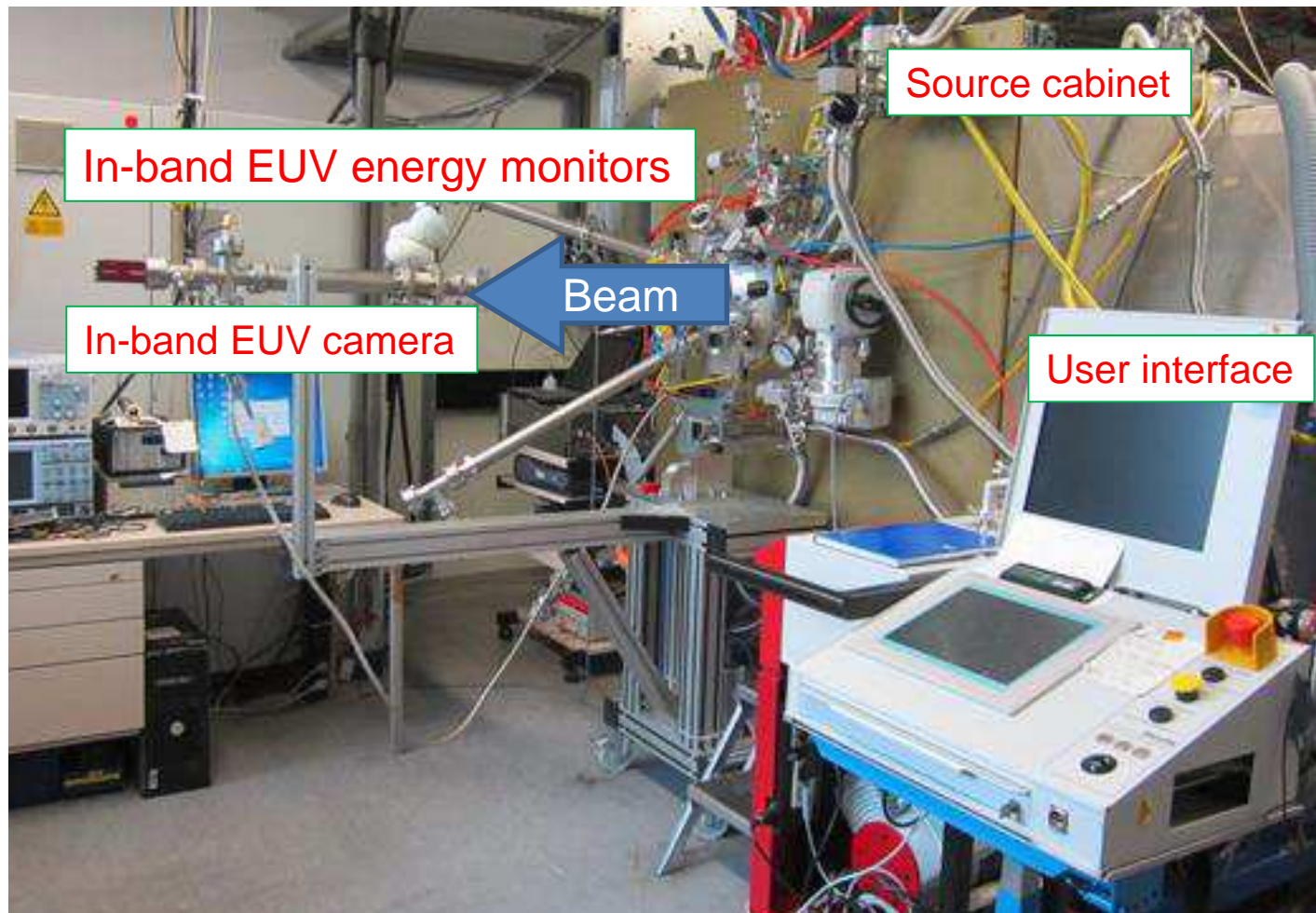


LDP: Stable and reliable

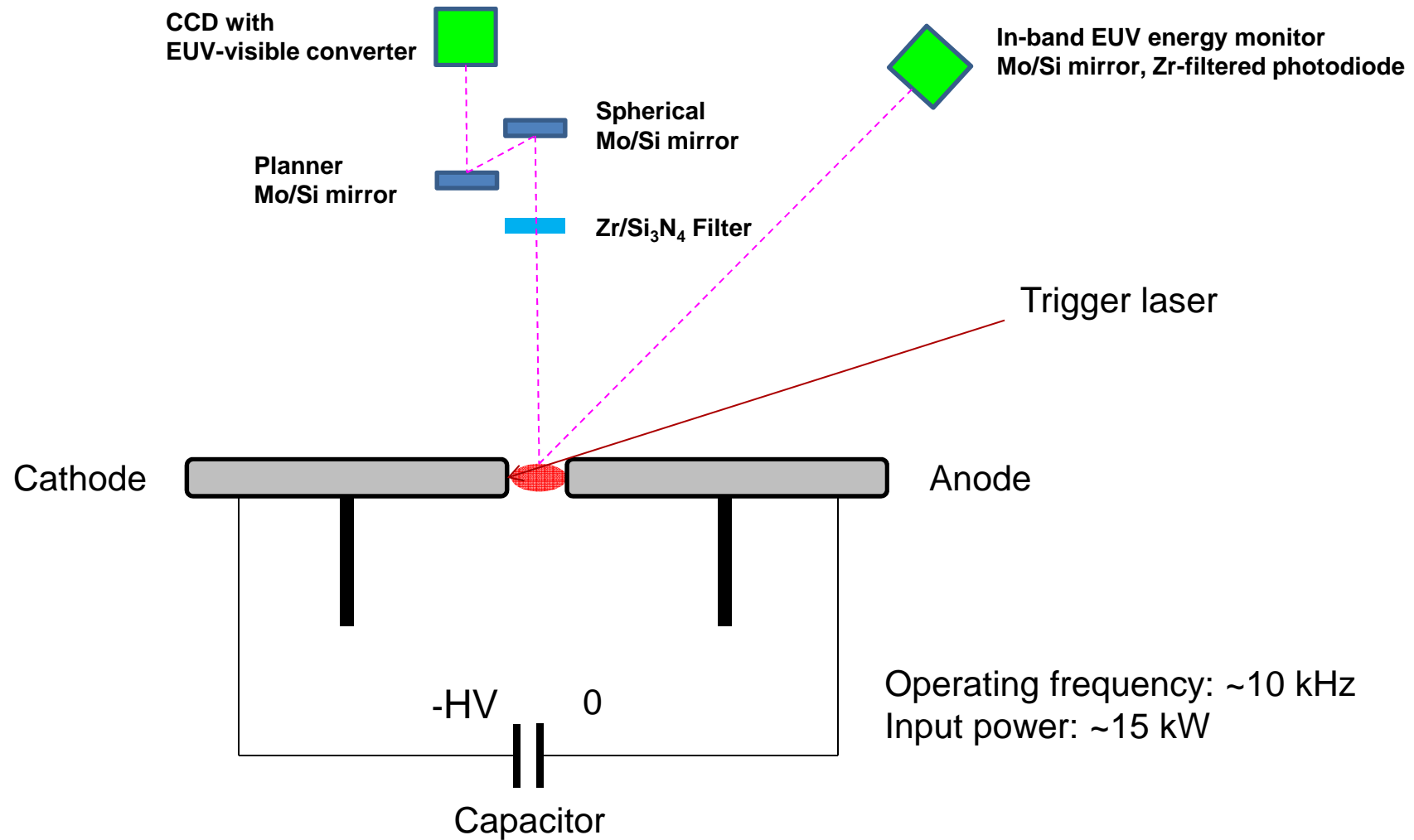
- **Tin is always available at all time (thin film) – No time discretization**
 - No timing error that would cause a loss of synchronization with the discharge
- **Tin is always at the same location – No spatial discretization**
 - No positional error that would result in instability in the conversion efficiency



Experimental system: PoC and debris-shield verification

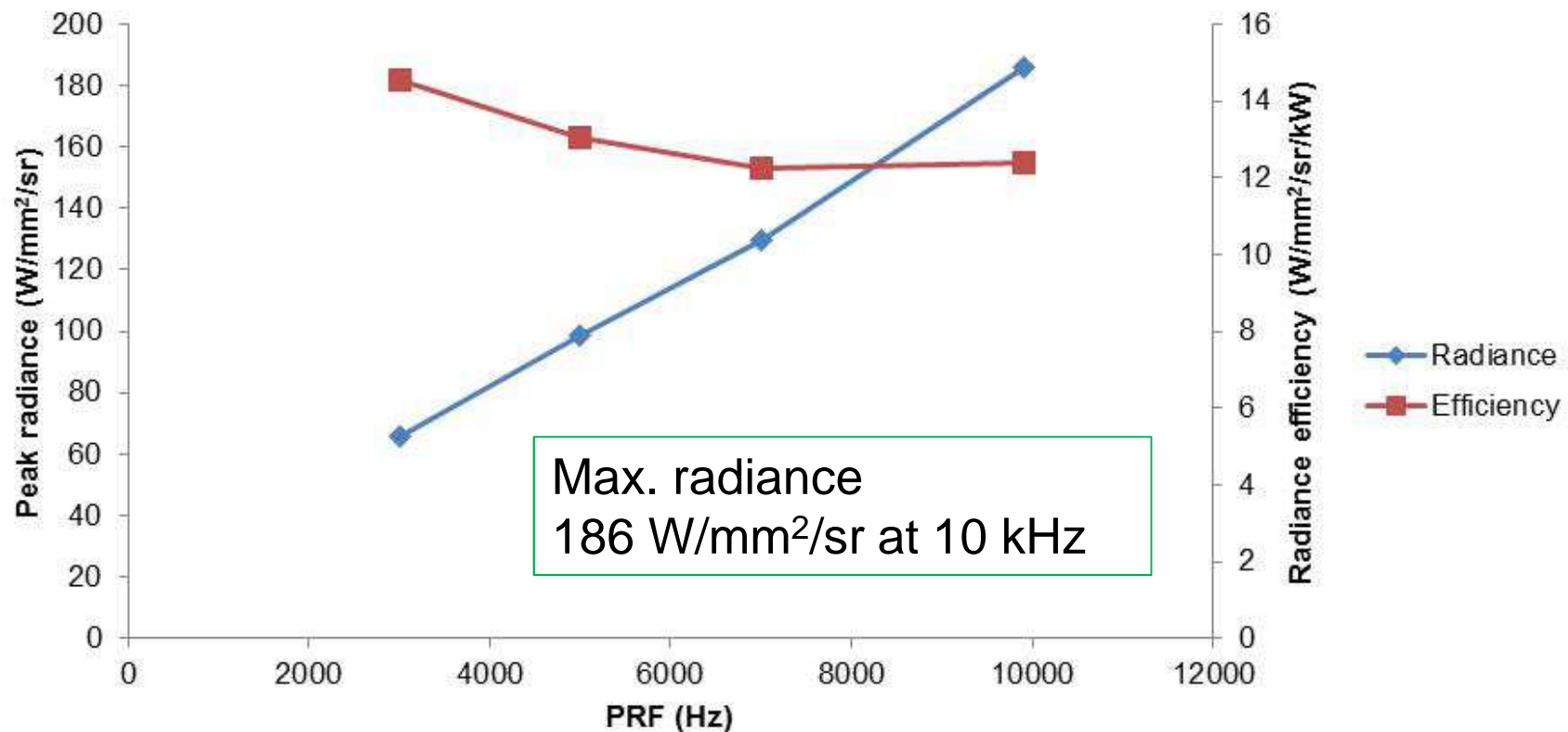


Radiance measurement

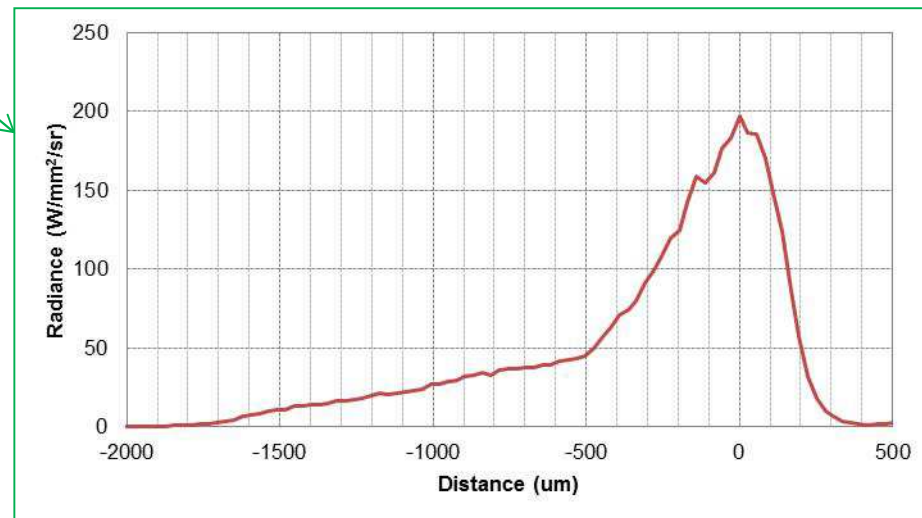
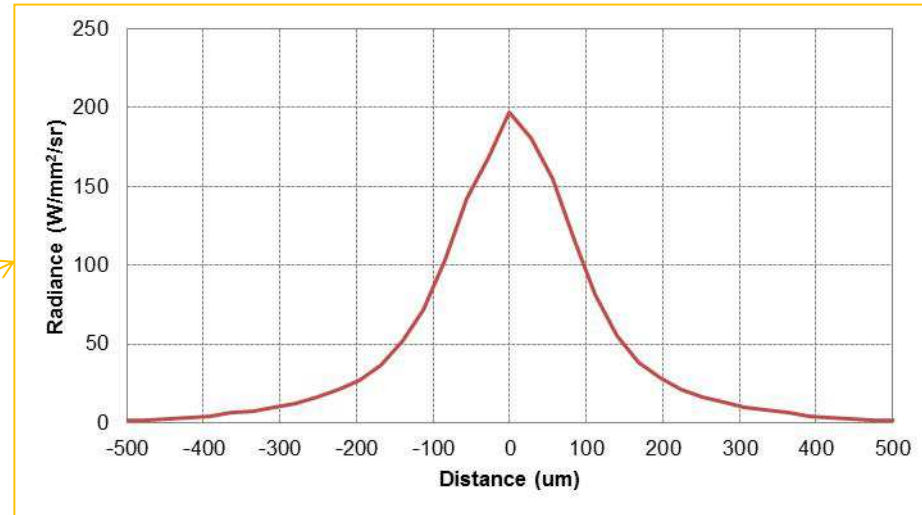
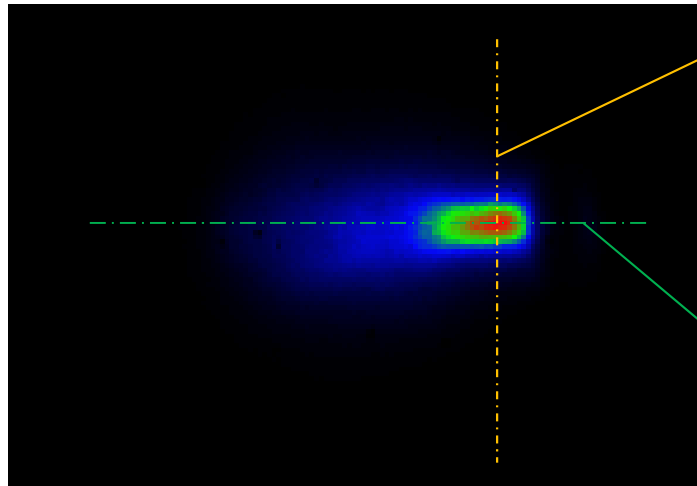


Pulse Repetition Frequency (PRF) scaling up to 10 kHz

- ❑ Measurement was done up to 15 kW, 10 kHz.
- ❑ Radiance linearity has been confirmed with relatively higher efficiency at low frequency region.
- ❑ High efficiency ($>12 \text{ W/mm}^2/\text{sr/kW}$) was maintained at 10 kHz. (ref. $\sim 1 \text{ W/mm}^2/\text{sr/kW}$ in case of Xe GDPP)

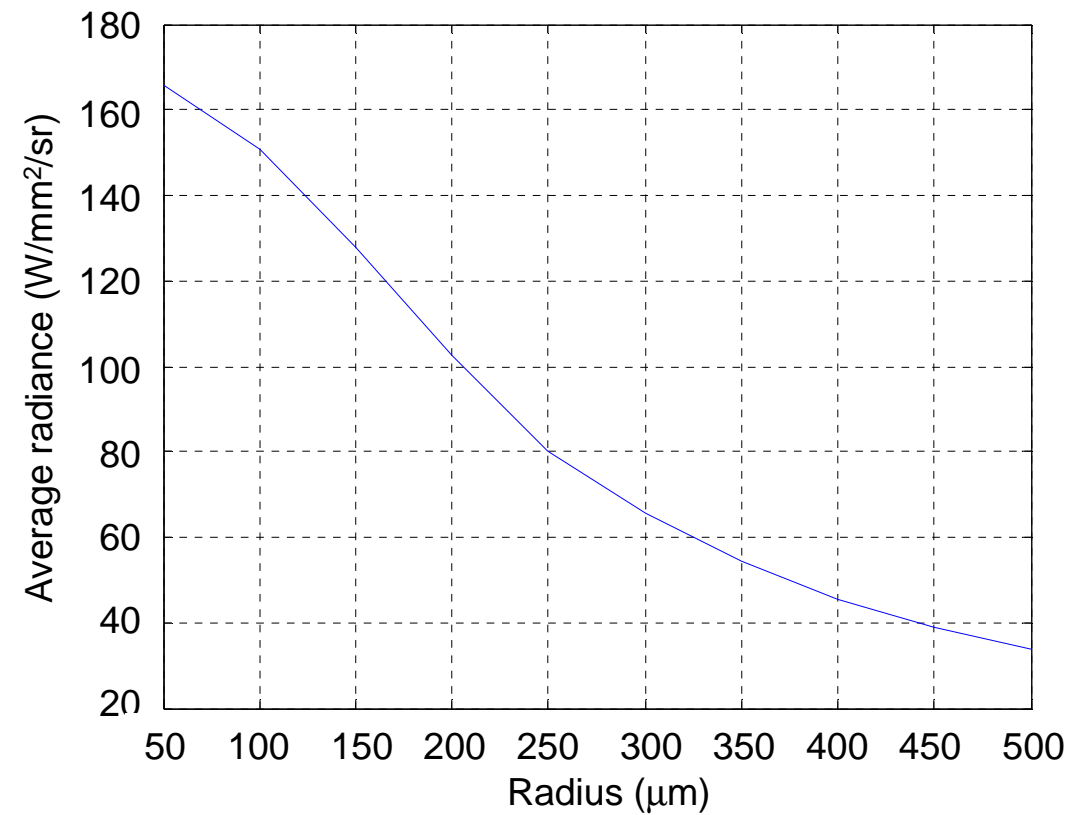
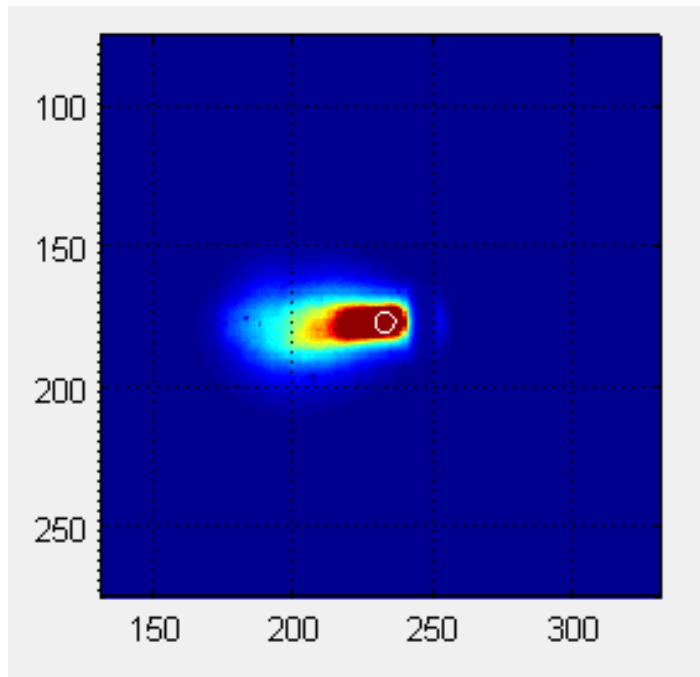


Emission image and profile 10 kHz



- ❑ Diameter: 200 μm (FWHM)
- ❑ Length: 450 μm (FWHM)

Averaged radiance vs plasma radius



Radiance stability at 10 kHz

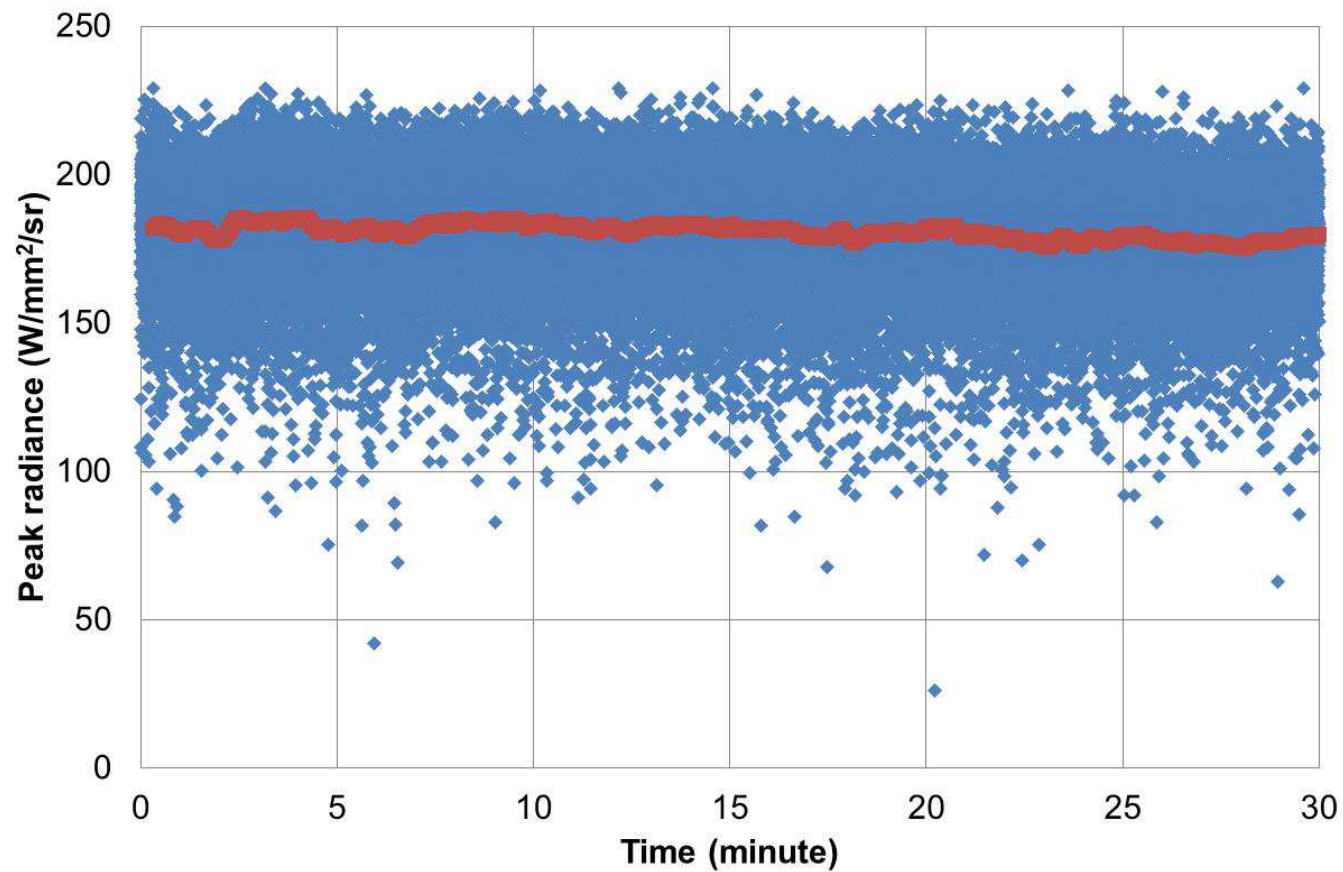
10 kHz (15 kW)

Dose-control off

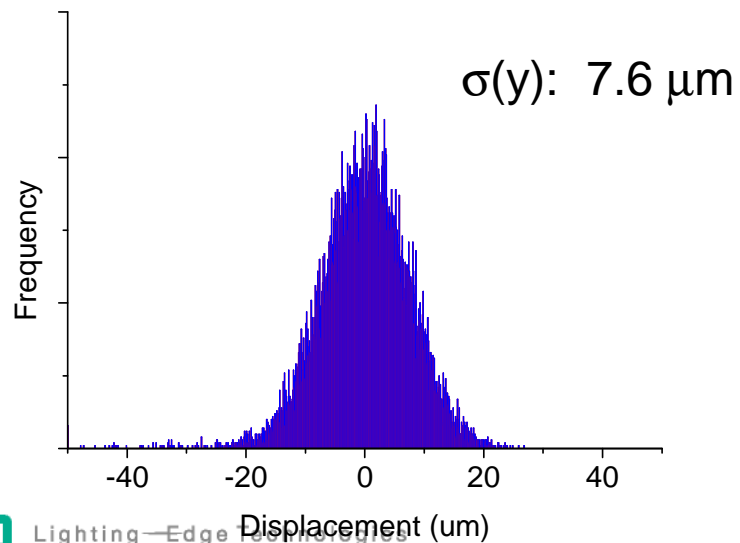
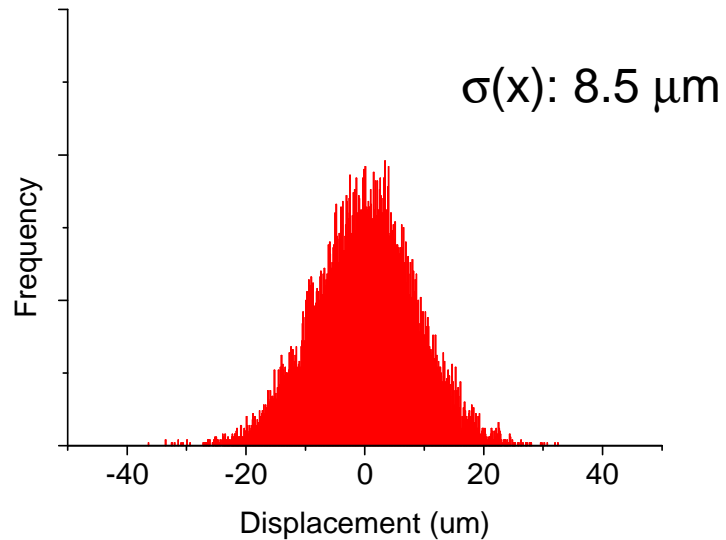
Duty cycle 100 %

Frame-to-frame deviation: 9.7 %

300-frame-average deviation: 1.4 %



Position stability at 10 kHz

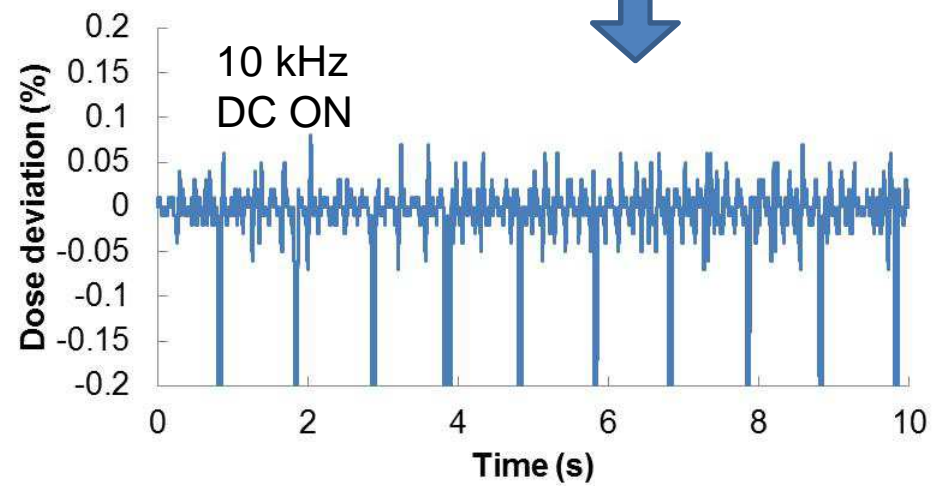
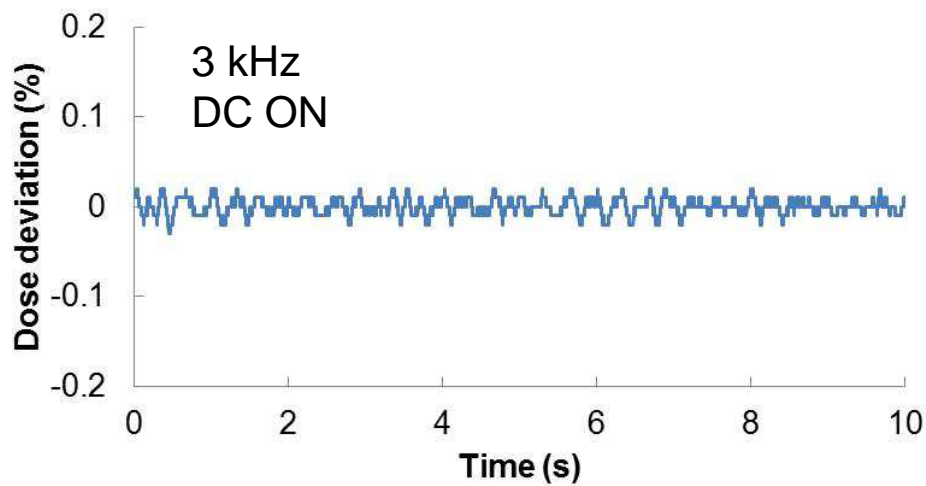
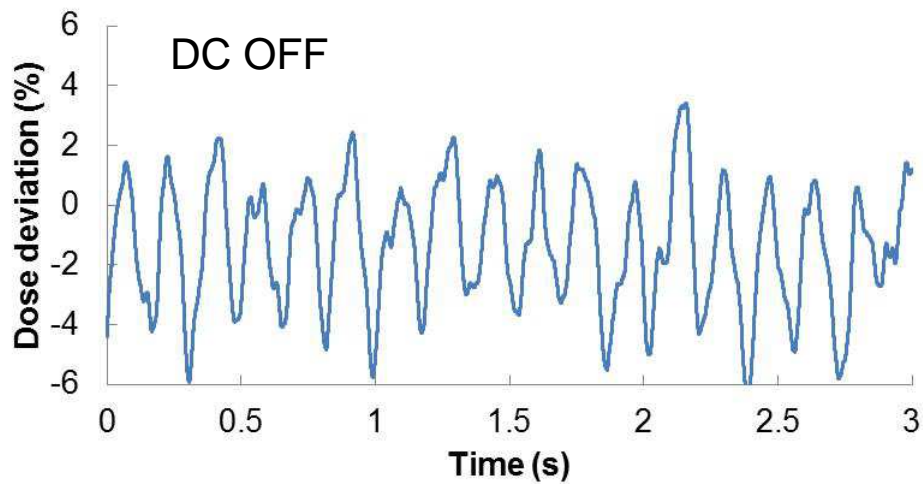


- ☐ Fluid dynamics
- ☐ Thermal stabilization
- ☐ Geometry



Energy/position stability improvement

Dose control test at 10 kHz



Periodic spikes will be eliminated by tuning dose-control software.

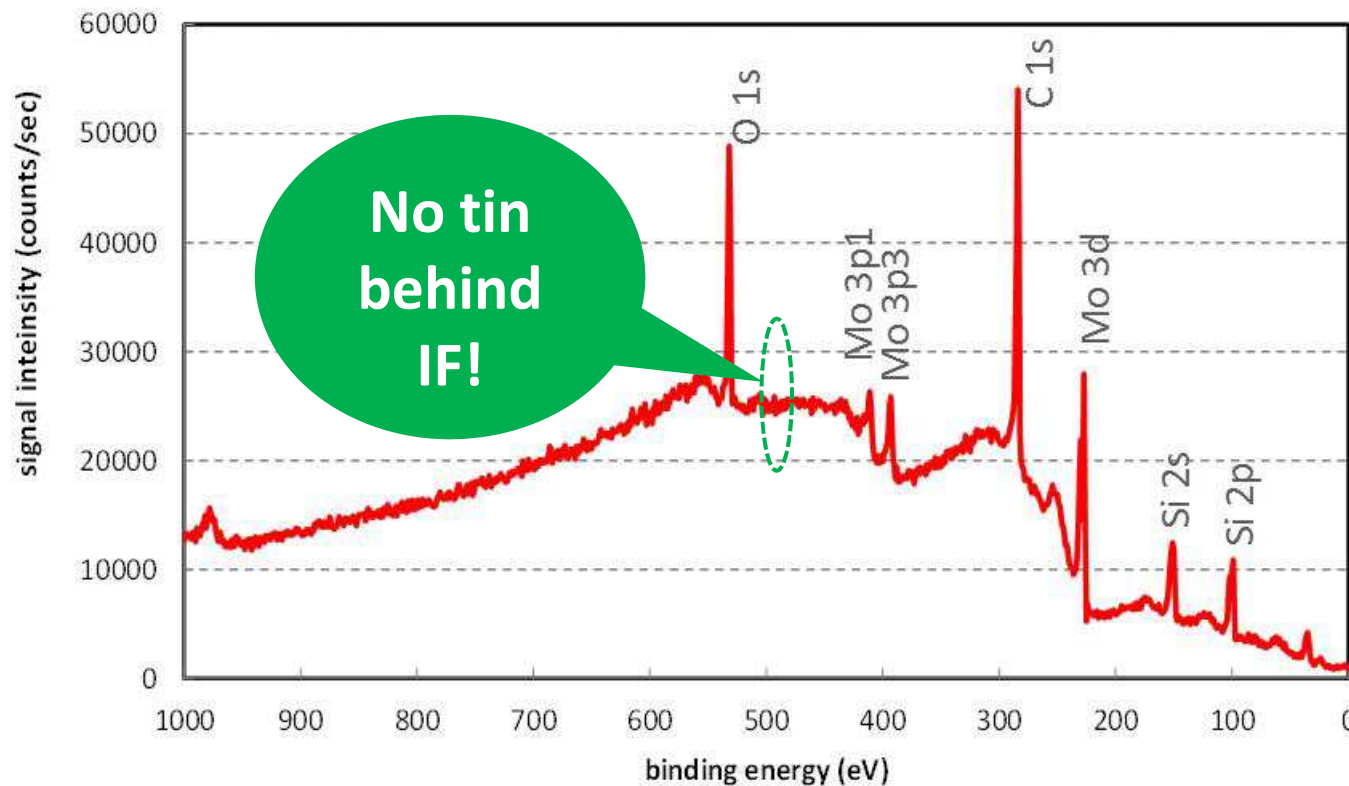
Dose control test at 10 kHz

Pulse repetition frequency		5 kHz	7 kHz	10 kHz DC OFF	10 kHz DC ON
E0	Stored energy	1.5 J	1.5 J	1.5 J	1.5 J
Average input	On capacitor	7.5 kW	10.5 kW	15 kW	15.2 kW
Peak radiance	At plasma	93 W/mm ² /sr	120 W/mm ² /sr	180 W/mm ² /sr	180 W/mm ² /sr
Energy	Pulse deviation	8.2 %	8.2 %	12.7 %	17.7 %
	Dose deviation	Not measured	Not measured	10%	<0.1 %
Radiance	Frame-to-frame deviation*	5.0 %	5.4 %	9.7 %	9.7 %
	Dose deviation**	0.7 %	0.7 %	1.4 %	0.7 %

* 1 frame = 1~2 ms exposure

** 300-frame moving average

Sample measurement after IF aperture in litho source



Conditions

Source input: 9 kW

Distance from IF: 200 mm

Exposure time: 6 hours

Estimated EUV intensity:
0.19 W/cm²

✓ No tin peak (485-487 eV)

- Tin is completely blocked in LDP source
 - Analysis depth → 3-5 nm
 - Resolution → 0.1 At%

Summary

- Peak radiance at reasonable input power (15 kW, 10 kHz), under which sufficient component lifetime is obtainable, is **180~200 W/mm²/sr** at plasma (90~100 W/mm²/sr after debris shield).

Performance summary (as of September 2013)

Item	Current performance	Remark
Pulse repetition frequency	10 kHz	Variable
Input power	15 kW	at capacitor
In-band EUV power	300 W/2 π sr	at plasma
Peak radiance efficiency	12 W/mm ² /sr/kW	at plasma
Peak radiance	180 W/mm ² /sr	at plasma
Average radiance (ϕ 200 mm)	150 W/mm ² /sr	at plasma
Plasma size	200×450 μ m	FWHM
Energy stability	12.7 % (pulse) 10 % (300-pulse dose)	at 10 kHz DC OFF
	17.7 % (pulse) 0.1 % (300-pulse dose)	at 10 kHz DC ON
Peak radiance stability	9.7 % (frame) 1.4 % (300 frame)	at 10 kHz DC OFF
	9.7 % (frame) 0.7 % (300 frame)	at 10 kHz DC ON
Position stability	~10 μ m	at 10 kHz



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